

Notice of References Cited	Application/Control No. 10/577,926		Applicant(s)/Patent Under Reexamination ABE ET AL.	
	Examiner MATTHEW G. KAYRISH		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,847,594	01-2005	Lee, Kyung-Geun	369/44.13
*	B	US-2002/0067666	06-2002	Maeda et al.	369/13.38
*	C	US-2001/0050888	12-2001	Eguchi et al.	369/47.48
*	D	US-6,088,307	07-2000	Fushimi et al.	369/44.13
*	E	US-2003/0021206	01-2003	Tomita, Yoshimi	369/53.23
*	F	US-7,224,651	05-2007	Ko et al.	369/47.27
*	G	US-2003/0002427	01-2003	Lee et al.	369/120
*	H	US-6,172,952	01-2001	Inokuchi et al.	369/47.55
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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